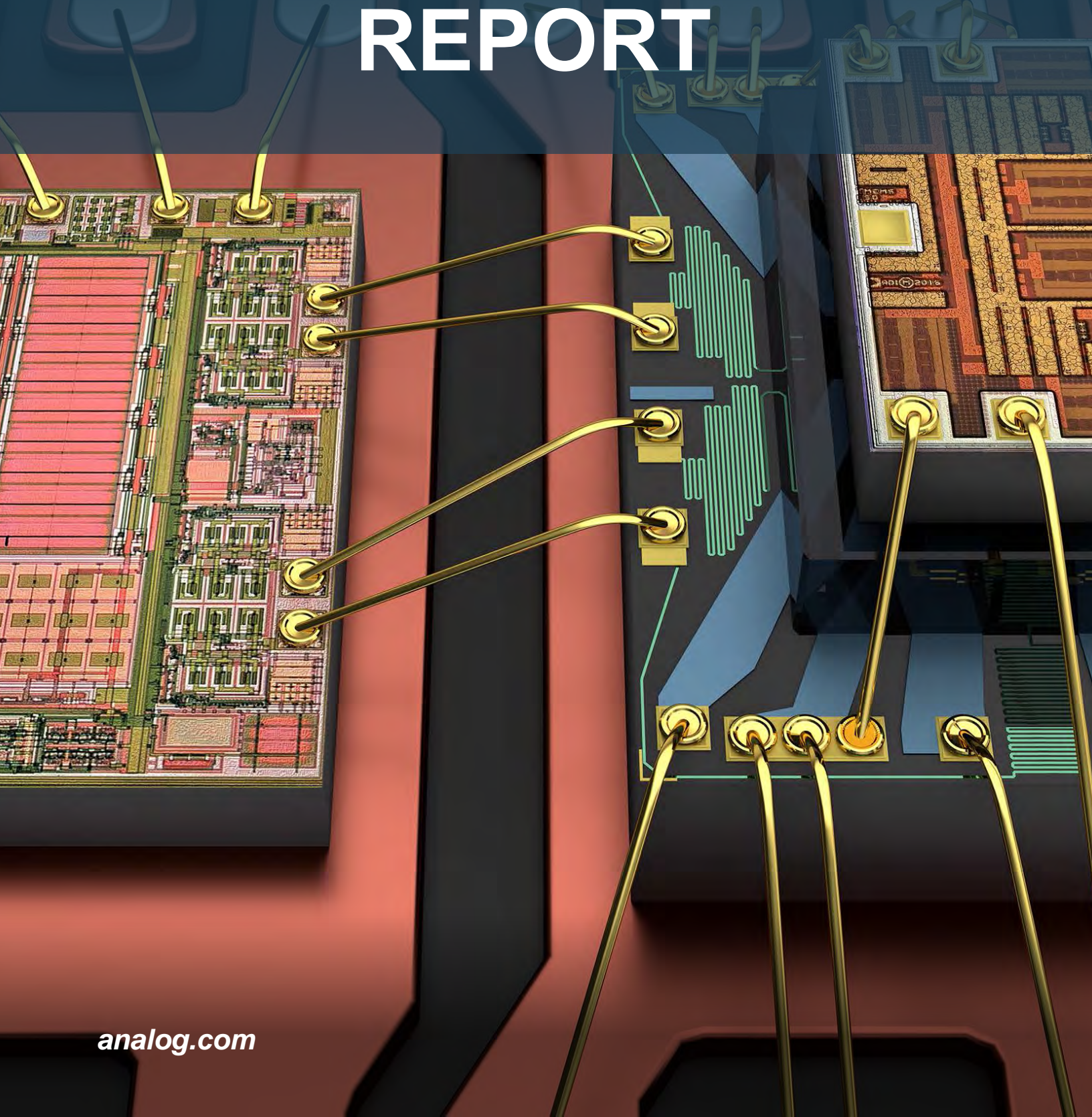


RELIABILITY REPORT



Reliability Data Report

Report Number: R582

LTC6811

Report generated on: Mon Oct 23, 2017

• OPERATING LIFE TEST					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS (+125°C)	No. of FAILURES
SSOP	1,108	1526	1650	346.40	0
	1,108			346.40	0
• HIGHLY ACCELERATED STRESS TEST AT +130°C/85%RH					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS (+85°C)	No. of FAILURES
SSOP	629	1422	1649	1,509.12	0
	629			1,509.12	0
• PRESSURE COOKER TEST AT 15 PSIG, +121°C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS	No. of FAILURES
SSOP	2,205	1422	1714	262.89	0
	2,205			262.89	0
• TEMPERATURE CYCLE FROM -65°C to +150°C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	No. of FAILURES
SSOP	1,700	1422	1714	639.80	0
	1,700			639.80	0
• THERMAL SHOCK FROM -65°C to +150°C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	No. of FAILURES
SSOP	1,612	1422	1714	330.60	0
	1,612			330.60	0
• HIGH TEMPERATURE BAKE +150°C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS	No. of FAILURES
SSOP	154	1451	1518	154.00	0
	154			154.00	0
• HIGH TEMPERATURE BAKE +175°C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS	No. of FAILURES
SSOP	176	1422	1648	176.00	0
	176			176.00	0

(1) Assumes Activation Energy= 0.7 Electron Volts
(2) Failure Rate Equivalent to +55 °C, 60% Confidence Level = 33.95 FITS
(3) Mean Time Between Failure in Years = 3,362
Note: 1 FIT = 1 Failure in One Billion Hours.
Note 2: HAST, Temp Cycle & Thermal Shock are subjected to J-STD-020 MSL1 Preconditioning